Search Notes



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Examiner

Hanh Nguyen

Applicant(s)/Patent Under Reexamination

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Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
709	231	10/8/08	hn
709	219		
709	218		
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714	4		
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370	242		
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370	252		
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707	102	10/8/08	hn

SEARCH NOTES

Search Notes	Date	Examiner
east	10/8/08	hn

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
370	230.1	10/8/08	hn
370	465		
370	412		
370	389		
709	227		
709	232	10/8/08	hn

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